

PRELIMINARY

FPD7612P70

HI-FREQUENCY PACKAGED PHEMT

PERFORMANCE

- 20 dBm Output Power (P_{1dB})
- 21 dB Power Gain (G_{1dB}) at 1.85 GHz
- 0.7 dB Noise Figure at 1.85 GHz
- 30 dBm Output IP3
- 50% Power-Added Efficiency at 1.85 GHz
- Evaluation Boards Available



GATE LEAD IS ANGLED

DESCRIPTION AND APPLICATIONS

The FPD7612P70 is a packaged depletion mode AlGaAs/InGaAs pseudomorphic High Electron Mobility Transistor (pHEMT). It utilizes a 0.25 µm x 200 µm Schottky barrier Gate, defined by high-resolution stepper-based photolithography. . The FPD7612 is also available in die form .

Typical applications include gain blocks and medium power stages for applications to 26 GHz.

ELECTRICAL SPECIFICATIONS AT 22°C

Parameter	Symbol	Test Conditions	Min	Тур	Max	Units					
RF SPECIFICATIONS MEASURED AT $f = 1850$ MHz USING CW SIGNAL (except as noted)											
Power at 1dB Gain Compression	P_{1dB}	$V_{DS} = 5 \text{ V}; I_{DS} = 50\% I_{DSS}$	The s	20	_ C C C	dBm					
Gain at 1dB Gain Compression	SSG	$V_{DS} = 5 \text{ V}; I_{DS} = 50\% I_{DSS}$		21	50	dB					
Power-Added Efficiency	PAE	$V_{DS} = 5 \text{ V}; I_{DS} = 50\% I_{DSS};$ $P_{OUT} = P_{1dB}$	- 101.11	45		%					
Maximum Stable Gain (S ₂₁ /S ₁₂)	MSG	$V_{DS} = 5 \text{ V}; I_{DS} = 50\% I_{DSS}$									
f= 12 GHz	ZSC.C	O pr		14							
f = 18 GHz				10							
Noise Figure	NF	$V_{DS} = 5 \text{ V}; I_{DS} = 25\% I_{DSS}$		0.7		dB					
Output Third-Order Intercept Point	IP3	$V_{DS} = 5V; I_{DS} = 50\% I_{DSS}$		30	47.V	dBm					
$P_{OUT} = 9 \text{ dBm SCL}$			100	7-17	000	3.5					
Saturated Drain-Source Current	I_{DSS}	$V_{DS} = 1.3 \text{ V}; V_{GS} = 0 \text{ V}$	45	60	75	mA					
Maximum Drain-Source Current	I_{MAX}	$V_{DS} = 1.3 \text{ V}; V_{GS} \cong +1 \text{ V}$		120		mA					
Transconductance	G_{M}	$V_{DS} = 1.3 \text{ V}; V_{GS} = 0 \text{ V}$		80		mS					
Gate-Source Leakage Current	I_{GSO}	$V_{GS} = -5 \text{ V}$		1	10	μΑ					
Pinch-Off Voltage	$ V_P $	$V_{DS} = 1.3 \text{ V}; I_{DS} = 0.2 \text{ mA}$	0.7	0.9	1.3	V					
Gate-Source Breakdown Voltage	$ V_{BDGS} $	$I_{GS} = 0.2 \text{ mA}$	12	14		V					
Gate-Drain Breakdown Voltage	$\left V_{BDGD}\right $	$I_{GD} = 0.2 \text{ mA}$	14.5	16		V					
Thermal Resistivity (see Notes)	θ_{JC}	$V_{DS} > 3V$		335		°C/W					

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ABSOLUTE MAXIMUM RATINGS¹

Parameter	Symbol	Test Conditions	Min	Max	Units
Drain-Source Voltage	V_{DS}	$-3V < V_{GS} < +0V$		8	V
Gate-Source Voltage	V _{GS}	$0V < V_{\rm DS} < +8V$		-3	V
Drain-Source Current	I_{DS}	For $V_{DS} > 2V$		I_{DSS}	mA
Gate Current	I_G	Forward or reverse current		5	mA
RF Input Power ²	P_{IN}	Under any acceptable bias state		60	mW
Channel Operating Temperature	T _{CH}	Under any acceptable bias state		175	°C
Storage Temperature	T_{STG}	Non-Operating Storage	-40	150	°C
Total Power Dissipation	P _{TOT}	See De-Rating Note below		450	mW
Gain Compression	Comp.	Under any bias conditions		5	dB
Simultaneous Combination of Limits ³		2 or more Max. Limits		80	%

 $^{{}^{1}}T_{Ambient} = 22^{\circ}C$ unless otherwise noted ²Max. RF Input Limit must be further limited if input VSWR > 2.5:1

Notes:

Operating conditions that exceed the Absolute Maximum Ratings will result in permanent damage to the device.

Total Power Dissipation defined as: $P_{TOT} = (P_{DC} + P_{IN}) - P_{OUT}$, where:

PDC: DC Bias Power P_{IN}: RF Input Power P_{OUT}: RF Output Power

Total Power Dissipation to be de-rated as follows above 22°C:

 P_{TOT} = 450mW – (3mW/°C) x T_{PACK}

where T_{PACK} = source tab lead temperature above 22 °C (coefficient of de-rating formula is the Thermal Conductivity)

Example: For a 65°C source lead temperature: $P_{TOT} = 450 \text{mW} - (3 \text{ x } (65 - 22)) = 321 \text{mW}$

HANDLING PRECAUTIONS

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To avoid damage to the devices care should be exercised during handling. Proper Electrostatic Discharge (ESD) precautions should be observed at all stages of storage, handling, assembly, and testing. These devices should be treated as Class 0 (< 250V) per JESD22-A114-B, Human Body Model, and Class A (< 200V) per JESD22-A115-A, Machine Model.

APPLICATIONS NOTES & DESIGN DATA

Applications Notes are available from your local Filtronic Sales Representative or directly from the factory. Complete design data, including S-parameters, noise data, and large-signal models are available on the Filtronic web site. Evaluation Boards available upon request.

http://www.filtrionic.co.uk/semis

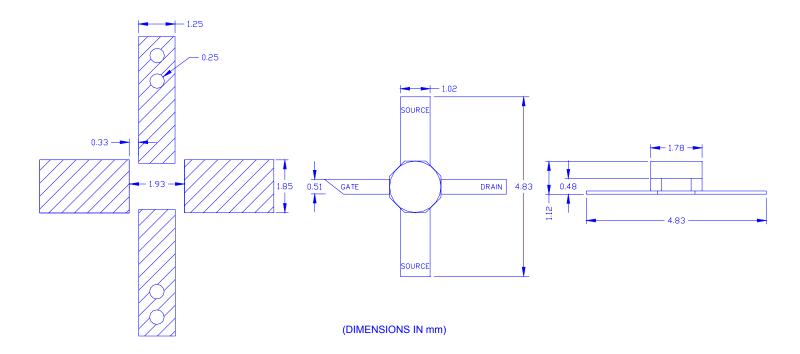
³Users should avoid exceeding 80% of 2 or more Limits simultaneously



BIASING GUIDELINES

- Active bias circuits provide good performance stabilization over variations of operating temperature, but require a larger number of components compared to self-bias or dual-biased. Such circuits should include provisions to ensure that Gate bias is applied before Drain bias, otherwise the pHEMT may be induced to self-oscillate. Contact your Sales Representative for additional information.
- > Dual-bias circuits are relatively simple to implement, but will require a regulated negative voltage supply for depletion-mode devices such as the FPD7612P70.
- For standard Class A operation, a 50% of I_{DSS} bias point is recommended. A small amount of RF gain expansion prior to the onset of compression is normal for this operating point. Note that pHEMTs, since they are "quasi- E/D mode" devices, exhibit Class AB traits when operated at 50% of I_{DSS}. To achieve a larger separation between P_{1dB} and IP3, an operating point in the 25% to 33% of I_{DSS} range is suggested. Such Class AB operation will not degrade the IP3 performance.

PACKAGE OUTLINE AND RECOMMENDED PC BOARD LAYOUT



All information and specifications subject to change without notice.

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